TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2267

Chopper Regulator, DC-DC Converter and Motor Drive Applications

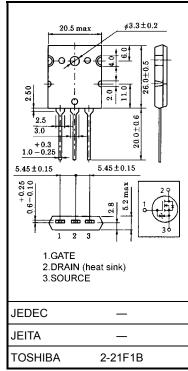
• 4-V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : R_{DS}\ (ON) = 8\ m\Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 60\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : I_{DSS} = 100\ \mu A\ (max)\ (V_{DS} = 60\ V) \\ \bullet & Enhancement\ mode & : V_{th} = 0.8 \sim 2.0\ V\ (V_{DS} = 10\ V,\ I_D = 1\ mA) \\ \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	60	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	60	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	I_{D}	60	Α
	Pulse (Note 1)	I_{DP}	240	Α
Drain power dissipation	n (Tc = 25°C)	P_{D}	150	W
Single pulse avalanche energy (Note 2)		E _{AS}	1054	mJ
Avalanche current		I _{AR}	60	Α
Repetitive avalanche energy (Note 3)		E _{AR}	15	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Unit: mm



Weight: 9.75 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	35.7	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 398 μ H, R_{G} = 25 Ω , I_{AR} = 60 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.

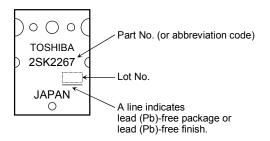
Electrical Characteristics (Ta = 25°C)

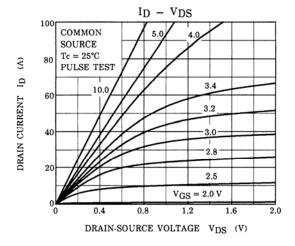
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ	
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V		_	100	μΑ	
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V	
Gate threshold v	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V	
Drain-source ON resistance		D	V _{GS} = 4 V, I _D = 30 A	_	12	15	mΩ	
Dialii-source Of	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 30 A	_	8	11	11177	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 30 A	40	60	-	S	
Input capacitano	e	C _{iss}			5400	_		
Reverse transfer capacitance		C _{rss}	v _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	920	_	pF	
Output capacitance		C _{oss}			2600	_		
Switching time	Rise time	t _r	V _{GS} _{OV}	_	30	_		
	Turn-on time	t _{on}	R _L =1Ω	_	60	_	ne	
	Fall time	t _f	$V_{DD} = 30V$ Duty \leq 1\%, t _w = 10\mus	_	65	_	- ns	
	Turn–off time	t _{off}		1	220	1		
Total gate charg plus gate–drain)	, and the second			170				
Gate-source charge		Q _{gs}	V _{DD} ≈ 48 V, V _{GS} = 10 V, I _D = 60 A		110		nC	
Gate-drain ("miller") charge		Q_{gd}			60	_		

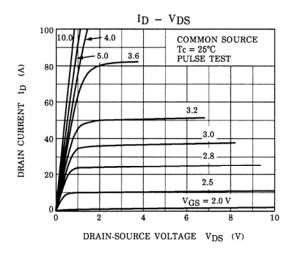
Source-Drain Ratings and Characteristics (Ta = 25°C)

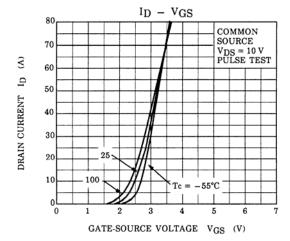
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	60	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	240	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 60 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 60 A, V _{GS} = 0 V	_	150	_	ns
Reverse recovered charge	Q _{rr}	dl _{DR} / dt = 50 A / μs	_	0.3	_	μC

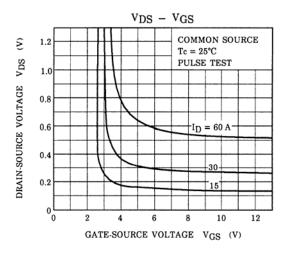
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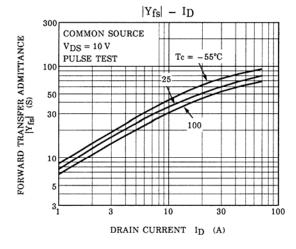


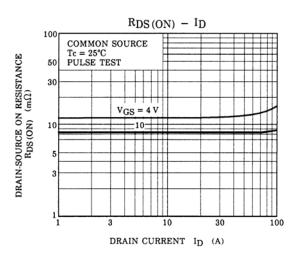


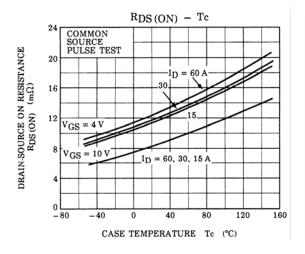


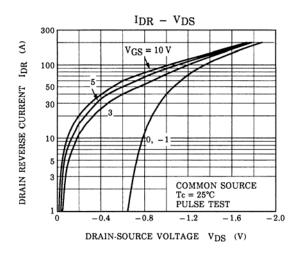


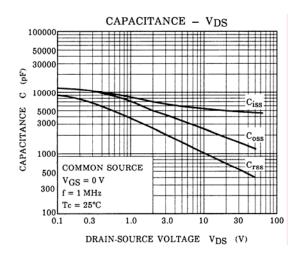


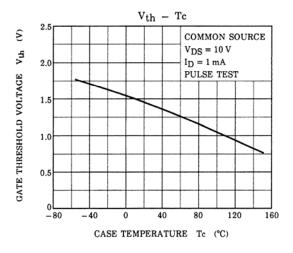


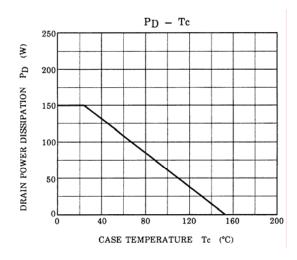


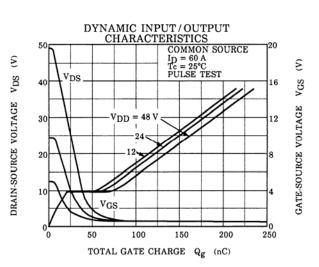




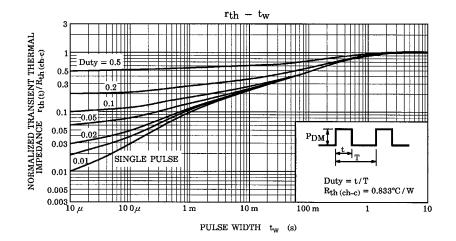


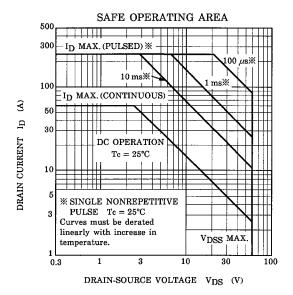


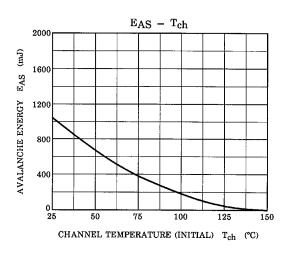


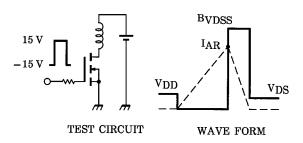


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$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 25~\text{V},~L = 398~\mu H \end{aligned} \qquad EAS &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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